

(12) INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(19) World Intellectual Property
Organization
International Bureau

(43) International Publication Date
12 December 2024 (12.12.2024)



(10) International Publication Number
WO 2024/253952 A1

- (51) **International Patent Classification:**
H01J 37/21 (2006.01) *H01J 37/28* (2006.01)
H01J 37/22 (2006.01) *G01N 23/2251* (2018.01)
- (21) **International Application Number:**
PCT/US2024/031800
- (22) **International Filing Date:**
31 May 2024 (31.05.2024)
- (25) **Filing Language:** English
- (26) **Publication Language:** English
- (30) **Priority Data:**
18/207,644 08 June 2023 (08.06.2023) US
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- (81) **Designated States** (*unless otherwise indicated, for every kind of national protection available*): AE, AG, AL, AM, AO, AT, AU, AZ, BA, BB, BG, BH, BN, BR, BW, BY, BZ, CA, CH, CL, CN, CO, CR, CU, CV, CZ, DE, DJ, DK, DM,

- DO, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, GT, HN, HR, HU, ID, IL, IN, IQ, IR, IS, IT, JM, JO, JP, KE, KG, KH, KN, KP, KR, KW, KZ, LA, LC, LK, LR, LS, LU, LY, MA, MD, MG, MK, MN, MU, MW, MX, MY, MZ, NA, NG, NI, NO, NZ, OM, PA, PE, PG, PH, PL, PT, QA, RO, RS, RU, RW, SA, SC, SD, SE, SG, SK, SL, ST, SV, SY, TH, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, WS, ZA, ZM, ZW.
- (84) **Designated States** (*unless otherwise indicated, for every kind of regional protection available*): ARIPO (BW, CV, GH, GM, KE, LR, LS, MW, MZ, NA, RW, SC, SD, SL, ST, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, RU, TJ, TM), European (AL, AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HR, HU, IE, IS, IT, LT, LU, LV, MC, ME, MK, MT, NL, NO, PL, PT, RO, RS, SE, SI, SK, SM, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, KM, ML, MR, NE, SN, TD, TG).
- Published:**
— *with international search report (Art. 21(3))*
— *before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments (Rule 48.2(h))*

(54) **Title:** AUTOFOCUS METHOD FOR SINGLE BEAM AND MULTI-BEAM SYSTEMS

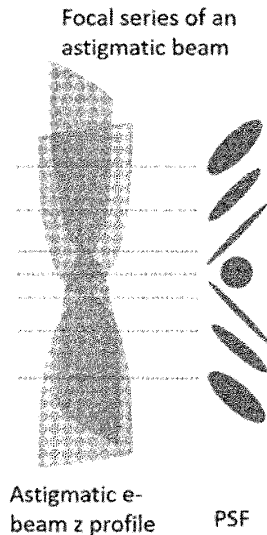


FIG. 2

(57) **Abstract:** An electron beam is directed at a workpiece on a stage with a first astigmatism applied. The electron beam reflected off the workpiece is detected and an image of the workpiece with the first astigmatism applied is generated. An autofocus model is applied to the image to determine a focus offset for the image with the autofocus model.

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